

Supporting Information

Exciton Dynamics and Annihilation in WS₂ 2D Semiconductors

Long Yuan and Libai Huang*

Department of Chemistry, Purdue University, West Lafayette, Indiana 47907, United States

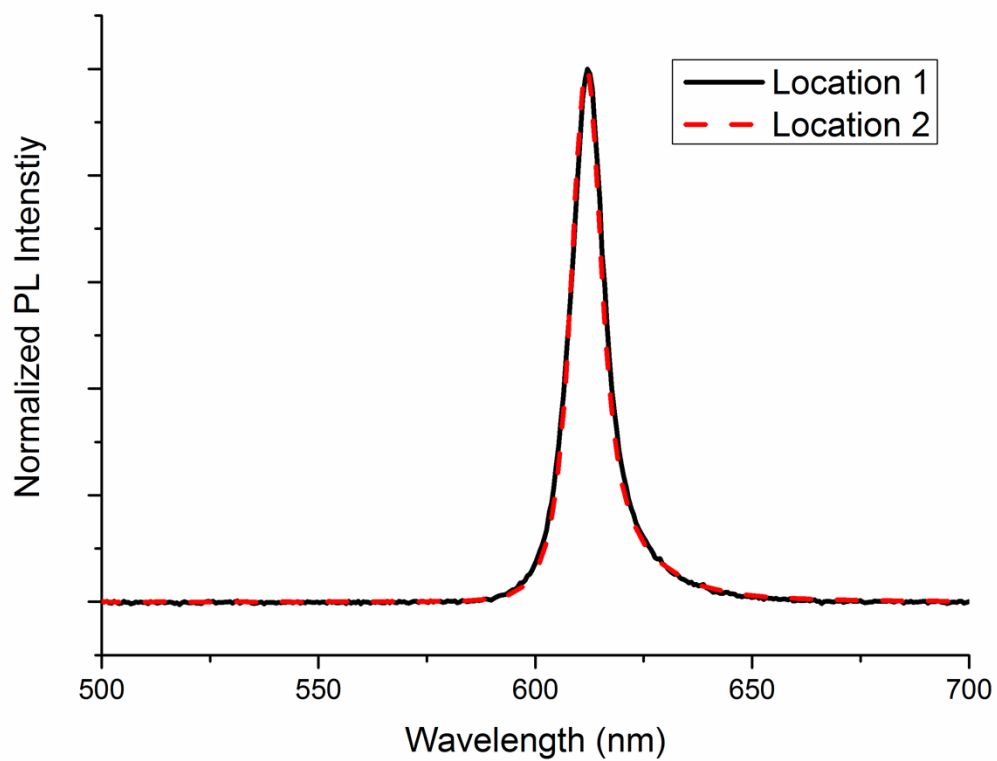


Fig.S1. *PL spectrum at different location for monolayer WS₂.*

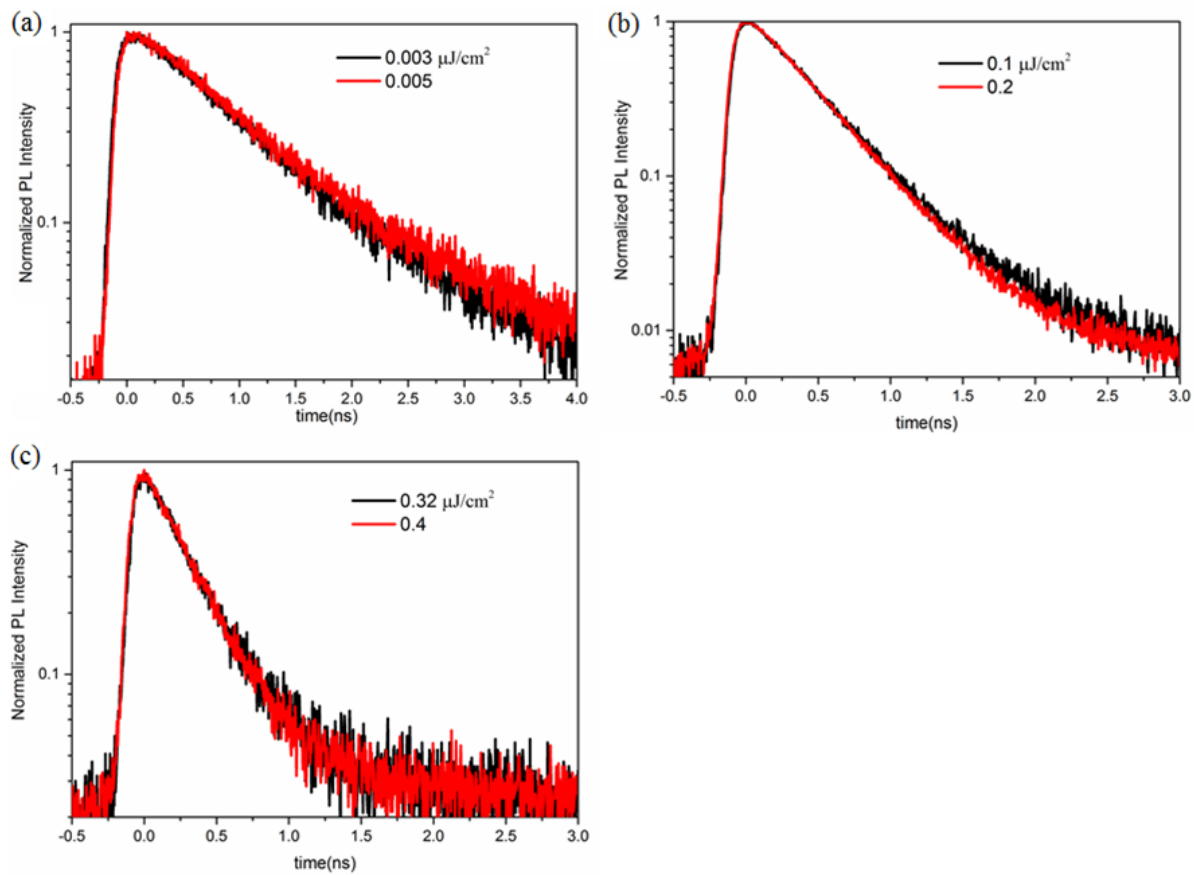


Fig. S2. PL decay at two different low excitation densities to obtain the exciton lifetime without annihilation for WS₂ (a) monolayer, (b) bilayer, and (c) trilayer.

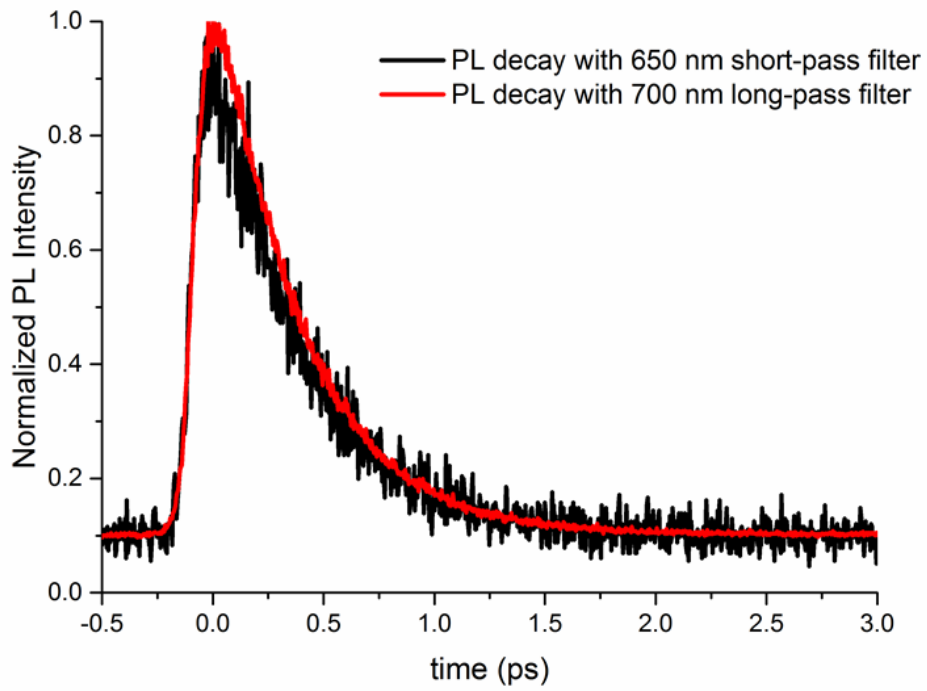


Fig. S3. PL decay with 650 nm short-pass filter (black line) and 700 nm long-pass filter (red line) in WS_2 bilayer at pump intensity of $0.2 \mu J/cm^2$.

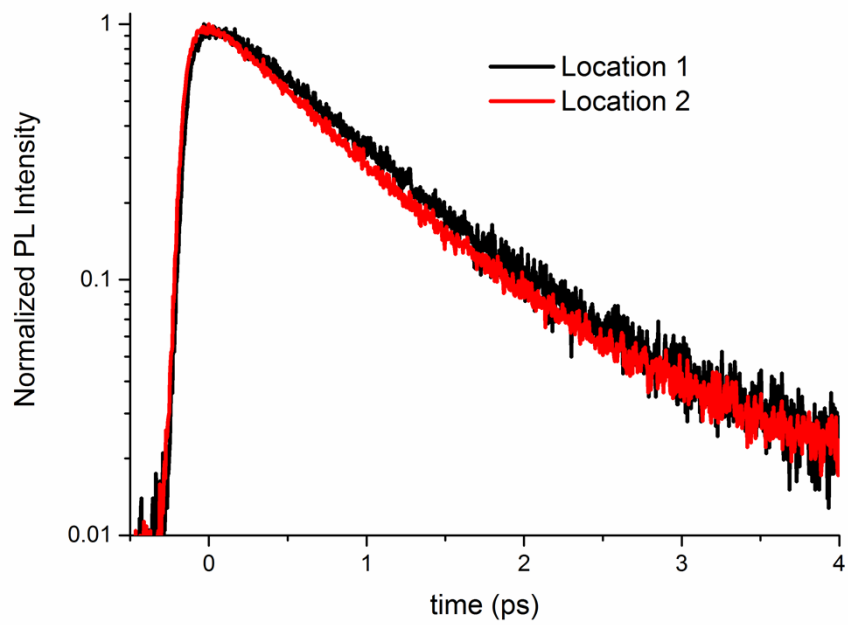


Fig. S4. *PL decay for WS_2 monolayer at different locations at pump intensity of 5 nJ/cm^2 .*

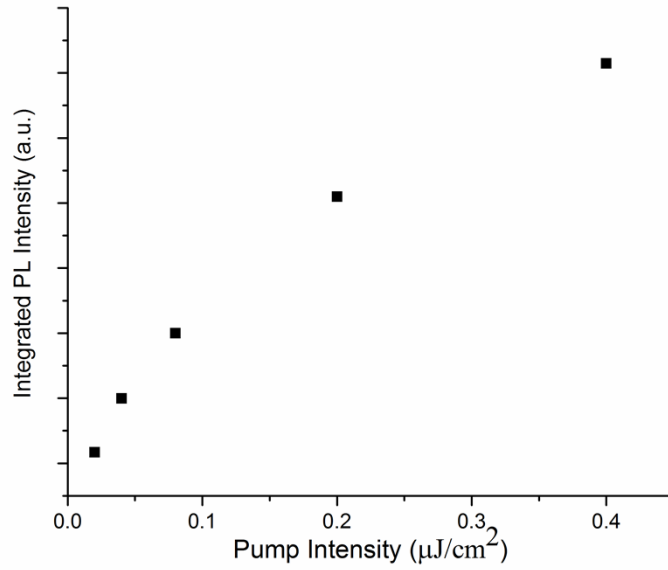


Fig. S5. Integrated PL intensity for monolayer WS_2 as a function of pump intensity.

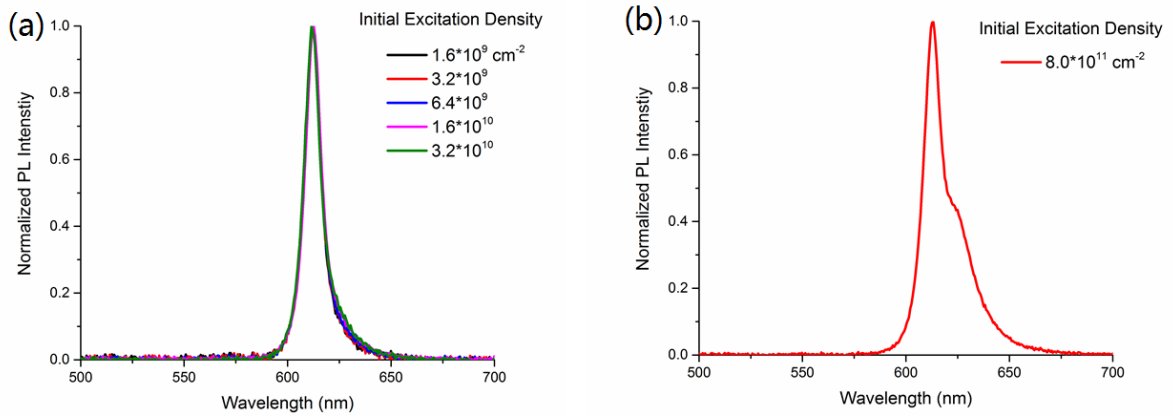


Fig S6. Evolution of PL spectra in WS_2 monolayer with the pumping intensity. We observed an obvious biexciton emission peak only at pump intensity great than $8.0 \cdot 10^{11} \text{ cm}^{-2}$ (b).

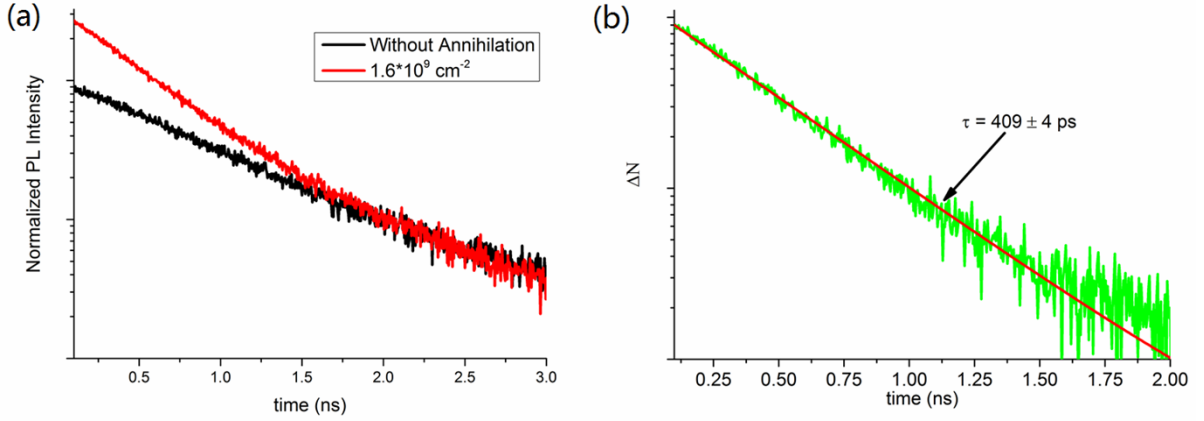


Fig. S7. (a) Normalize the decay curves at the low pump intensity (without annihilation) and high exciton density ($1.6 \times 10^9 \text{ cm}^{-2}$) at the long delay time of 2 ns. (b) The subtracted decay curve at the low pump intensity from the high pump intensity and fit the subtracted curve with a single exponential decay. The obtained annihilation time is ~ 400 ps.

Quantum yield measurements

We measured the quantum yield of WS₂ monolayer, bilayer, and trilayer following the method referring in previous study¹. We used a calibrated reference consisting of a thin film of rhodamine-6G dye molecules. The films were prepared by spin coating a glass substrate with a concentrated methanol solution of rhodamine-6G. We firstly calibrated the absolute QY of our reference film using the methanol solution of rhodamine-6G, which has a quantum yield of 100%. With this reference, we then determined the QY of WS₂ films.

Reference

1. Mak, K. F. L., C.; Hone, J.; Shan, J.; Heinz, T. F., *Phys. Rev. Lett.* 2010, **105**, 136805.